DISCRETE SEMICONDUCTORS

DATA SHEET

BT132 series DTriacs logic level

Product specification

January 1998



NXP Semiconductors Product specification

Triacs logic level

BT132 series D

GENERAL DESCRIPTION

Glass passivated, sensitive gate triacs in a plastic envelope, intended for use in general purpose bidirectional switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

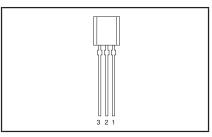
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
V _{DRM} I _{T(RMS)} I _{TSM}	Repetitive peak off-state voltages RMS on-state current Non-repetitive peak on-state current	500D 500 1 16	600D 600 1 16	V A A

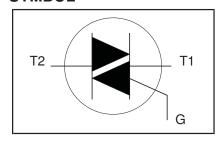
PINNING - TO92

PIN	DESCRIPTION			
1	main terminal 2			
2	gate			
3	main terminal 1			

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	. MAX.		UNIT
V_{DRM}	Repetitive peak off-state voltages		-	-500 500 ¹	-600 600 ¹	>
I _{T(RMS)}	RMS on-state current Non-repetitive peak on-state current	full sine wave; T _{lead} ≤51 °C full sine wave; T _j = 25 °C prior to surge	-	-	1	A
l²t dl _⊤ /dt	I ² t for fusing Repetitive rate of rise of	t = 20 ms t = 16.7 ms t = 10 ms $I_{TM} = 1.5 \text{ A}$; $I_{G} = 0.2 \text{ A}$;	- - -	17	6 7.6 28	A A A ² s
·	on-state current after triggering	$\begin{array}{c} d _G^n/dt = 0.2 \; \mbox{Å}/\mu \mbox{s} \\ & T2 + \; \mbox{G} + \\ & T2 + \; \mbox{G} - \\ & T2 - \; \mbox{G} - \\ & T2 - \; \mbox{G} + \\ \end{array}$	- - -	5 5	0 0 0 0	Α/μs Α/μs Α/μs Α/μs
$ \begin{vmatrix} I_{GM} \\ V_{GM} \\ P_{GM} \\ P_{G(AV)} \\ T_{stg} \\ T_{j} \end{vmatrix} $	Peak gate current Peak gate voltage Peak gate power Average gate power Storage temperature Operating junction temperature	over any 20 ms period	- - - -40	0 1	5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5	Α A V W C C

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¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 3 $A/\mu s$.

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THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-lead}	Thermal resistance junction to lead Thermal resistance junction to ambient	full cycle half cycle pcb mounted;lead length = 4mm		- - 150	60 80 -	K/W K/W K/W

STATIC CHARACTERISTICS

 $T_i = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I _{GT}	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$				
		T2+ 0		2.0	5	mA
		T2+ 0		2.5	5 5	mA
		T2- G		2.5		mA
		T2- G	+ -	5.0	10	mA
l IL	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$				
		T2+ 0		1.6	10	mA
		T2+ 0		4.5	15	mA
		T2- G		1.2	10	mA
		T2- G	+ -	2.2	15	mA
I _H	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	-	1.2	10	mA
V_{T}	On-state voltage	$I_T = 5 A$ $V_D = 12 V; I_T = 0.1 A$	-	1.4	1.70	V
$\left egin{array}{c} oldsymbol{I_{H}} \\ oldsymbol{V_{T}} \\ oldsymbol{V_{GT}} \end{array} \right $	Gate trigger voltage	$ V_D = 12 V; I_T = 0.1 A$		0.7	1.5	V
		$IV_D = 400 \text{ V}$: $I_T = 0.1 \text{ A}$: $T_i = 125 \text{ °C}$	0.25	0.4	-	V
I_{D}	Off-state leakage current	$V_{D} = V_{DRM(max)}; T_{j} = 125 ^{\circ}C$	-	0.1	0.5	mA

DYNAMIC CHARACTERISTICS

 $T_i = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
	Critical rate of rise of	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125 ^{\circ}C;$	-	5	-	V/µs
t _{gt}	off-state voltage Gate controlled turn-on time	exponential waveform; $R_{GK} = 1 \text{ k}\Omega$ $I_{TM} = 6 \text{ A}$; $V_D = V_{DRM(max)}$; $I_G = 0.1 \text{ A}$; $dI_G/dt = 5 \text{ A}/\mu s$	-	2	-	μs

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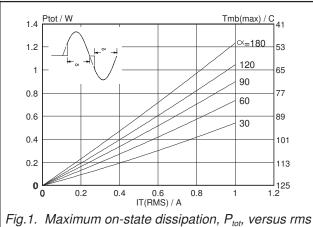


Fig.1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_{T(RMS)}$, where α = conduction angle.

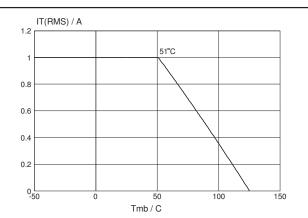


Fig.4. Maximum permissible rms current $I_{T(RMS)}$, versus lead temperature T_{lead} .

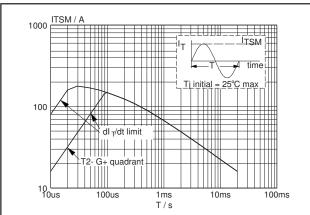


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \le 20$ ms.

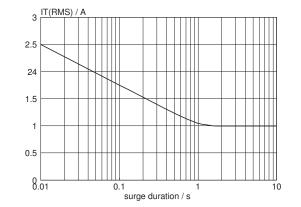


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{lead} \le 51 \,^{\circ}\text{C}$.

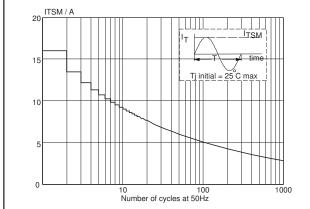


Fig.3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, f = 50 Hz.

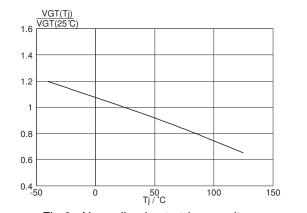
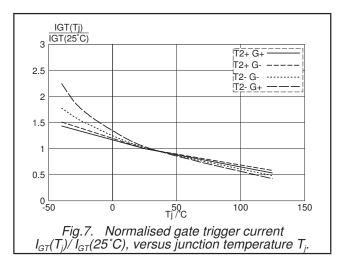


Fig.6. Normalised gate trigger voltage $V_{GT}(T_i)/V_{GT}(25^{\circ}C)$, versus junction temperature T_i

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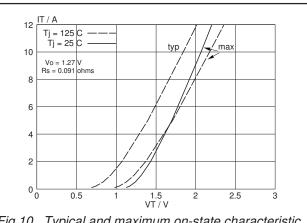
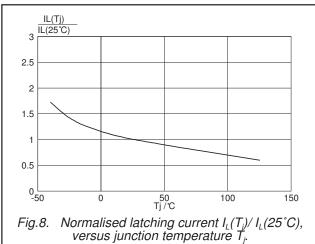


Fig. 10. Typical and maximum on-state characteristic.



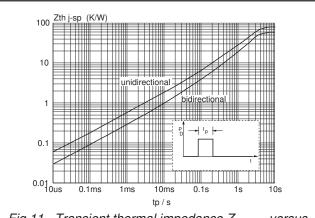
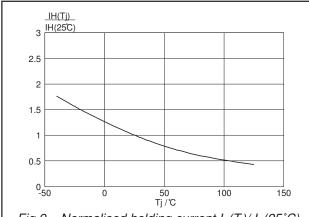


Fig.11. Transient thermal impedance $Z_{th j-lead}$, versus pulse width t_p .



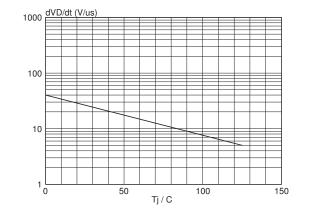


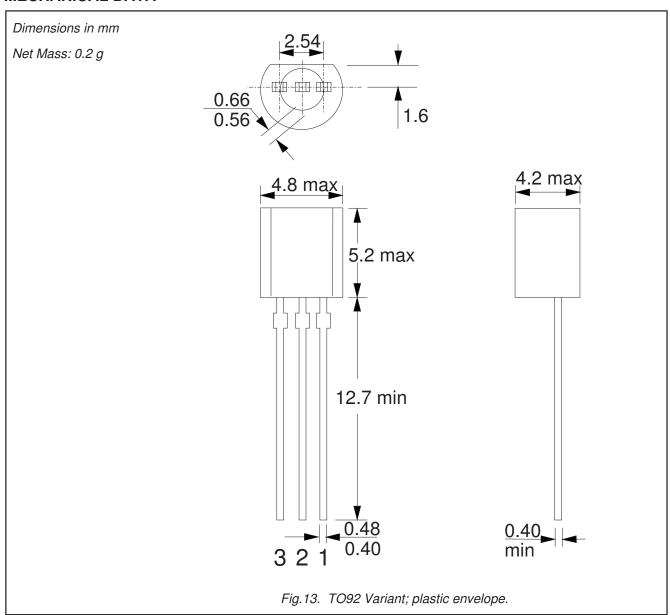
Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}C)$, versus junction temperature T_i .

Fig.12. Typical, critical rate of rise of off-state voltage, dV_D/dt versus junction temperature T_{j} .

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MECHANICAL DATA



Notes
1. Epoxy meets UL94 V0 at 1/8".

Legal information

DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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